

1 dB cm⁻¹, which encourages the belief that further process improvement may reduce average losses to below this value.

Discussion: We believe that the reason that guiding in Langmuir films has not previously been reported is that sufficiently thick films of good optical quality are difficult to produce. Even with our carefully optimised process we observed that, although the initial 150 to 200 were relatively defect free, the final layers were damaged by pin holes and cracking. A typical defect structure is illustrated in Fig. 2b. We have studied the relative scattering of the TE₀ and TM₀ modes by means of the mode lines from a prism coupler and have concluded that the increased defect density in the final layers accounts for the generally high attenuation for both TE and TM modes. However, the TM₀ mode is better confined than the TE₀ mode, interacts less with the defective region and should therefore exhibit lower losses. In our experiments, the losses are often larger for the TM₀ mode; this may be explained by the film molecules being tilted slightly with respect to the film plane. In this situation, the TE plane wave is relatively little affected, while the TM mode (in which the two electrical field components interact with both n_e and n_o) is more strongly influenced, and enhanced scattering results.

Conclusion: We have demonstrated that Langmuir films of fatty-acid salts may be deposited, by a carefully optimised process, in layers which are sufficiently thick to form optical waveguides. The thickness and refractive index, and thus the propagation constant, of such waveguides may be precisely selected. The average attenuation loss in these guides is relatively low (≈ 5 dB cm) and there is evidence that the intrinsic loss is even lower (1 dB cm⁻¹) for single-mode-order structures.

Clearly, the achievement of precisely-predictable-propagation-velocity waveguides has immediate application to several device concepts, such as planar couplers. The additional facility of refractive-index and anisotropy selection by CH chain length, metal-ion inclusion and possibly by bonding aromatic side chains onto the molecule extend the applications further, e.g. fibre-film couplers. The incorporation of dyes into Langmuir films has been demonstrated.⁴ This, and the metal-ion inclusions, suggest the possibility of planar laser structures using suitable Langmuir-film materials as the inert matrix.

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STACKING TECHNIQUES FOR LINEAR CODES

Indexing term: Error-correction codes

A procedure for subspace stacking is proposed, and it is proved that the technique is equally successful for both linear codes and anticodes. It is demonstrated that families of error-correcting codes may be constructed using the proposed technique for stacking linear codes. Examples of such codes are given with rates better than the best known codes of identical Hamming distance and the same number of information digits.

Introduction: A linear (n, k, d) error-correcting code is a set of q^k n -tuples that forms a subspace V of the vector space V_n over a Galois field of q elements $GF(q)$, with a minimum Hamming distance d . The codebook (array) $|0|$ is an array consisting of n columns and q^k rows,¹ the first k columns being the information part of the array and the last $n-k$ columns the parity-check (redundant) columns. The properties of subspace arrays with a maximum Hamming distance of, say, δ have been studied²⁻⁶, and such a subspace U of vector space U_m is called an (m, k, δ) linear anticode.²

The techniques for stacking linear anticodes were introduced by Farrell² and developed further by Farrell and Farrag.³ These stacking techniques are basically procedures for stacking a given anticode array $|0|$ and its inverse array $|I|$ (the rows of $|I|$ are logical complements of the corresponding rows of $|0|$) in such a way that the resulting array is a new linear anticode array. The purpose of this letter is to show that the anticode array stacking techniques can be generalised to subspaces which exhibit minimum and maximum distance properties; such a subspace V of V_n over $GF(q)$ is denoted by $(n_v, k_v, d_v, \delta_v)$ to indicate that V has a minimum Hamming distance d_v and maximum Hamming distance δ_v , i.e. the distance d between any two vectors in V lies between the limits $d_v \leq d \leq \delta_v$.

General stacking technique: For any two given subspaces V and U , there exists a subspace Z which results from stacking U on V . The rules of stacking and the parameters of the resulting subspace Z are given by the following theorem.

Theorem: If each of the zero elements and the nonzero elements of an $(n_v, k_v, d_v, \delta_v)$ subspace array $|0_v|$ are replaced by an $(n_u, k_u, d_u, \delta_u)$ subspace array $|0_u|$ and its inverse $|I_u|$, respectively, the resulting $(n_z, k_z, d_z, \delta_z)$ subspace array $|0_z|$ has the following parameters:

$$n_z = n_v n_u$$

$$k_z = k_v + k_u$$

d_z = smallest of the following three expressions:

$$(1) n_v d_u$$

$$(2) n_u d_v$$

$$(3) n_v \delta_u + n_u \delta_v - 2\delta_v \delta_u$$

δ_z = largest of the following two expressions:

$$(1) n_v \delta_u$$

$$(2) n_u \delta_v$$

Proof: Let v be a vector of weight w in the $(n_v, k_v, d_v, \delta_v)$ subspace array $|0_v|$. If each of the zero elements and each of the nonzero elements of v are replaced by the array $|0_u|$ and its inverse $|I_u|$, respectively, the resulting array has $n_v n_u$ columns and q^{k_u} rows. The minimum and maximum weight of these q^{k_u} row vectors may be determined as follows. Let the i th row vector be z :

(1) If $w = 0$, z consists of n_v n_u -tuple vectors, such as u (vector u is the i th row vector of $|0_u|$). Since the minimum and maximum weights of the subspace U , excluding the all-zero row vector, are d_u and δ_u , respectively, the lowest possible weight of z for $w = 0$, $w_{z(min)}|_{w=0}$, excluding the all-zero row vector, is therefore $n_v d_u$, and the largest possible weight of z , $w_{z(max)}|_{w=0}$, is therefore $n_v \delta_u$.

Table 1

Weight of vector v (w)	Corresponding minimum weight of z for a given weight of v ($w_{z(min)} w$)	Corresponding maximum weight of z for a given weight of v ($w_{z(max)} w$)
0	$\begin{bmatrix} n_v d_u \\ n_u d_v \end{bmatrix}$	$\begin{bmatrix} n_v d_u \\ n_v d_u - d_v(2\delta_u - n_u) \end{bmatrix}$
d_v	$n_u(d_v + p)$	$n_v d_u - (d_v + p)(2\delta_u - n_u)$
$d_v + p$	$n_u(n_v/2)$	$n_u(n_v/2)$
$n_v/2$	$n_u(n_v/2) - j(2\delta_u - n_u)$	$n_u(n_v/2) + j$
$n_v/2 + j$	$n_v \delta_u + n_u \delta_v - 2\delta_v \delta_u$	$\begin{bmatrix} n_u \delta_v \end{bmatrix}$

Table 2

Stacked codes (n_v, k_v, d_v, δ_v) and (n_u, k_u, d_u, δ_u)	New code Z (n_z, k_z, d_z)	$d_{L, d_{up}}$
(2, 1, 1, 1), (60, 8, 28, 32)	(120, 9, 56) (119, 9, 55)	54, 57
(2, 1, 1, 1), (59, 8, 27, 32)	(118, 9, 54) (117, 9, 53)	52, 56
(31, 5, 16, 16), (3, 2, 2, 2)	(93, 7, 46) (92, 7, 45)*	44, 45

* This code can also be found by the Solomon and Stiffler⁸ puncturing technique
 d_L = Helgert and Stinaff⁷ lower bounds on minimum Hamming distance
 d_{up} = Helgert and Stinaff⁷ upper bounds on minimum Hamming distance

This form of the matrix does not directly generate the systematic form of the code; however, the reduced echelon form of $[G_z]$ may be obtained by simple elementary row operations.¹

A few examples of new codes found by code stacking are given in Table 2.

Comments: The weight distribution of some classes of linear codes are known^{9, 10} so d and δ for such codes can be determined and thus the appropriate families of stacked codes can be constructed. It is useful to note that if code U is stacked on code V , where both V and U are cyclic codes, the resulting code Z , by definition, is a quasicyclic code. The useful properties of quasicyclic codes may therefore be extended to construct encoding and decoding algorithms for codes derived by the stacking procedure.

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HYDROGEN SENSITIVITY OF PALLADIUM-THIN-OXIDE-SILICON SCHOTTKY BARRIERS

Indexing terms: Metal-insulator-semiconductor structures, Schottky effect, Tunnelling

It is shown that current transport through Schottky barriers formed by Pd on n -type silicon with a thin thermally grown oxide is sensitive to hydrogen in the ambient. It is shown that a transition from minority- to majority-carrier dominated current occurs with increasing hydrogen pressure.

Metal-thin-oxide-silicon Schottky barriers have been described by several authors.¹⁻⁴ The thin oxide decreases the density of surface states considerably, which otherwise would dominate the I/V characteristics of the barriers. The energy barrier between the metal and the semiconductor is therefore largely determined by the difference in their work functions. It has been shown theoretically and experimentally that, with a thin oxide layer, both minority- and majority-carrier dominated structures can be obtained.²⁻⁴ In the first case, the current through the structure is determined by minority carriers diffusing to the interface between the semiconductor and the oxide, and their tunnelling through the oxide. In the second case, the current is dominated by thermally excited majority carriers tunnelling through the oxide ('normal Schottky current').

We have recently shown that hydrogen introduces a dipole layer at the interface between catalytically active metals like Pd and Pt and an insulator. This changes the energy barrier at the interface, i.e. the work-function difference between the metal and the semiconductor on which the insulator is grown.⁶⁻¹⁰ Hydrogen is dissociated on the outer metal surface and dissolved in the metal in atomic form. Some of the dissolved hydrogen is adsorbed onto the metal-insulator interface, where it gives rise to a dipole layer. The description above is for temperatures and hydrogen con-

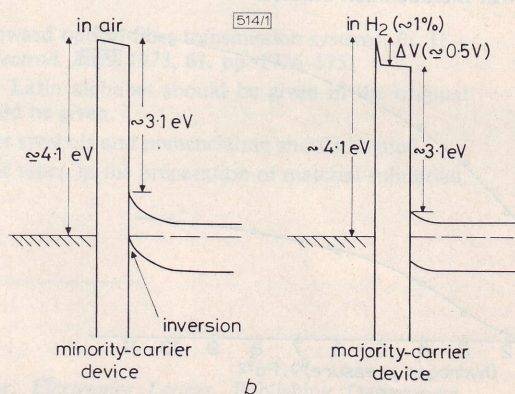
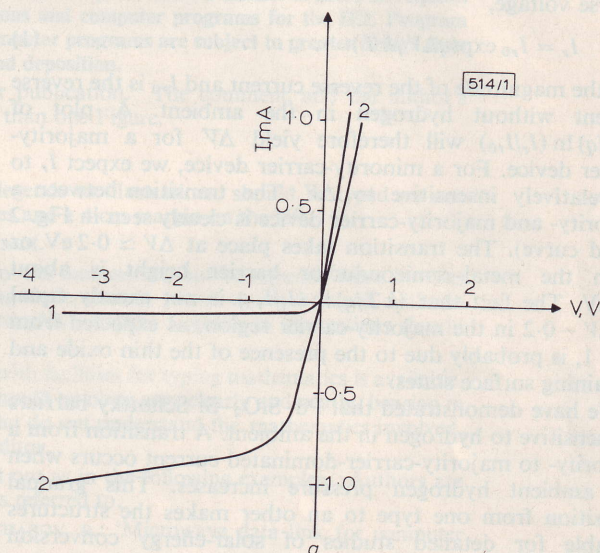


Fig. 1

(a) I/V curves of a Pd-SiO₂- n -type-Si Schottky barrier in air (curve 1) and in a small amount of hydrogen, 1% H₂, in air (curve 2). The temperature of the Schottky barrier was 150°C.

(b) Schematic band diagram of the Schottky barrier in air (left) and in hydrogen (right), respectively. In air (curve 1 in a), the current is dominated by minority carriers. In 1% H₂ (curve 2 in a), the current is dominated by majority carriers.